Japan Specified Radio Test Report

Report No.	:	**1812C60330212502**
Applicant	:	**Shenzhen Liuxing Technology Co., Ltd.**
Address	:	**5/F, Building A, North District, Qianhai Shen-Hong KongYouth Innovation and Enterpreneur Hub, Shenzhen, Guangdong Province, China**
Product Name	:	**MindPalace-Pocket2**
Report Date	:	**2026-07-08**

Shenzhen Anbotek Compliance Laboratory Limited

Contents

1. General Information 6
1.1. Client Information 6
1.2. Description of Device (EUT) 6
1.3. Auxiliary Equipment Used During Test 8
1.4. Description of Test Configuration 8
1.5. Test Conditions 8
1.6. Test Voltage 8
1.7. Test Equipment List 9
1.8. Description of Test Facility 10
1.9. Disclaimer 10
1.10. Measurement Uncertainty 11
2. Summary of Test Results 12
3. Frequency Tolerance Test 13
3.1. Test Limit 13
3.2. Test Setup 13
3.3. Test Procedure 13
3.4. Test Data 13
4. Antenna Power Test 14
4.1. Test Limit 14
4.2. Test Setup 14
4.3. Test Configuration 14
4.4. Test Data 14
5. Occupied Bandwidth (99%) Test 15
5.1. Test Limit 15
5.2. Test Setup 15
5.3. Test Procedure 15
5.4. Test Data 15
6. Spurious Emissions Intensity Test 16
6.1. Test Limit 16
6.2. Test Setup 16
6.3. Test Procedure 16
6.4. Test Data 16
7. Interference prevention function 17
7.1. Test Limit 17
7.2. Test Setup 17
7.3. Test Configuration 17
7.4. Test Data 17
8. Secondary Radiated Emissions Test 18
8.1. Test Limit 18
8.2. Test Setup 18

8.3. Test Configuration 18
8.4. Test Data 18
APPENDIX I -- TEST SETUP PHOTOGRAPH 19
APPENDIX II -- EXTERNAL PHOTOGRAPH 19
APPENDIX III -- INTERNAL PHOTOGRAPH 19

TEST REPORT

Applicant	:	Shenzhen Liuxing Technology Co., Ltd.
Manufacturer	:	Shenzhen Liuxing Technology Co., Ltd.
Product Name	:	MindPalace-Pocket2
Model No.	:	Pocket2 Pro, Rakusoku Scan Handy1, Pocket2
Trade Mark	:	留形科技 MANIFOLD TECH
Rating(s)	:	Input: 12V⎓ 2A Battery Capacity: 14.54VDC, 3500mAh
Test Standard(s)	**:**	**MIC Notice No.88 Appendix No.43** **Article 2, paragraph 1, item 19**

The device described above is tested by Shenzhen Anbotek Compliance Laboratory Limited to determine the maximum emission levels emanating from the device and the severe levels of the device can endure and its performance criterion. The measurement results are contained in this test report and Shenzhen Anbotek Compliance Laboratory Limited is assumed full of responsibility for the accuracy and completeness of these measurements. Also, this report shows that the EUT (Equipment Under Test) is technically compliant with the MIC Notice No.88 Appendix No.43 and Certificate regulation article 2, paragraph 1, item 19 requirements.

This report applies to above tested sample only and shall not be reproduced in part without written approval of Shenzhen Anbotek Compliance Laboratory Limited.

Date of Receipt	2026-06-15
Date of Test	2026-06-15 to 2026-07-03
Prepared By	Cecilia Chen (Cecilia Chen)
Approved & Authorized Signer	Jules Guo (Jules Guo)

Revision History

Report Version	Description	Issued Date
R00	Original Issue.	2026-07-08

1. General Information

1.1. Client Information

Applicant	:	Shenzhen Liuxing Technology Co., Ltd.
Address	:	5/F, Building A, North District, Qianhai Shen-Hong KongYouth Innovation and Enterpreneur Hub, Shenzhen, Guangdong Province, China
Manufacturer	:	Shenzhen Liuxing Technology Co., Ltd.
Address	:	5/F, Building A, North District, Qianhai Shen-Hong KongYouth Innovation and Enterpreneur Hub, Shenzhen, Guangdong Province, China
Factory	:	Shenzhen Liuxing Technology Co., Ltd.
Address	:	Room 213, 2/F, Area B, Qianhai Zhichuang Technology Industrial Park, No. 60 Nanchang Road, Xixiang Street, Bao'an District, Shenzhen City, Guangdong Province, China

1.2. Description of Device (EUT)

Product Name	:	MindPalace-Pocket2
Model No.	:	Pocket2 Pro, Rakusoku Scan Handy1, Pocket2 (For models differences: Pocket2 Pro: Black casing, ships with camera; Rakusoku Scan Handy1: Silver casing, ships without camera (the camera does not affect wireless functionality; it is external and detachable); Pocket2: Blue casing, ships without camera (only the model number and appearance color are different from “Rakusoku Scan Handy1”); According the model differences, we prepare "Pocket2 Pro" for test only.)
Trade Mark	:	留形科技 MANIFOLD TECH
Test Power Supply	:	14.54VDC Battery inside
Test Sample No.	:	1-2-1(Normal Sample), 1-2-2(Engineering Sample)
Hardware Version	:	20250812
Software Version	:	0.0.1
Adapter	:	N/A
RF Specification		
Operation Mode	:	☒ BT BLE
Support Rate	:	☒ 1Mbps ☒ 2Mbps

Operation Frequency	:	2402~2480MHz
Number of Channel	:	40 Channels
Modulation Type	:	GFSK
Antenna Type	:	FPC Antenna
Antenna Gain(Peak)	:	3.89dBi
Rated output Power	:	Bluetooth BLE_1M: 0.5mW Max. Bluetooth BLE_2M: 0.5mW Max.
Remark: (1) All of the RF specification are provided by customer. (2) For a more detailed features description, please refer to the manufacturer's specifications or the User's Manual.		

1.3. Auxiliary Equipment Used During Test

Title	Manufacturer	Model No.	Serial No.
Lenovo Computer	Lenovo	ThinkPad E485	/

1.4. Description of Test Configuration

The EUT has been tested under typical operating condition. The Applicant provides software to control the EUT for staying in continuous transmitting and receiving mode for testing.

Channel	Freq. (MHz)	Channel	Freq. (MHz)	Channel	Freq. (MHz)	Channel	Freq. (MHz)	Channel	Freq. (MHz)
00	**2402**	09	2420	18	2438	27	2456	36	2474
01	2404	10	2422	**19**	**2440**	28	2458	37	2476
02	2406	11	2424	20	2442	29	2460	38	2478
03	2408	12	2426	21	2444	30	2462	**39**	**2480**
04	2410	13	2428	22	2446	31	2464		
05	2412	14	2430	23	2448	32	2466		
06	2414	15	2432	24	2450	33	2468		
07	2416	16	2434	25	2452	34	2470		
08	2418	17	2436	26	2454	35	2472		

Note: EUT was tested with channel 00, 19 and 39.

1.5. Test Conditions

	Normal Test Conditions
Temperature	15°C - 35°C
Relative Humidity	45% - 75%
Pressure Range	86-106kPa

1.6. Test Voltage

Power Supply Voltage Fluctuation Test

Voltage Fluctuation Test	Normal Voltage	High Voltage +10% of Normal Voltage	Low Voltage -10% of Normal Voltage
Input To EUT	DC 14.54V	DC 15.99V	DC 13.09V
Output To RF Module	DC 3.30V	DC 3.30V	DC 3.30V
Voltage Variation (%)	--	0.00%	0.00%

Note: Voltage Variation (%)=(Output high or Low Voltage - Output Normal Voltage)/ Output Normal Voltage* 100

For extreme voltage test, we have tested the relationship between the external power supply and RF IC power supply. Base on the test results, only the normal voltage was selected to perform all items.

1.7. Test Equipment List

Item	Equipment	Manufacturer	Model No.	Last Cal.	Cal.Due Date
1	Spectrum Analyzer	Rohde & Schwarz	FSV40-N	2025-12-29	2026-12-28
2	MXA Spectrum Analysis	KEYSIGHT	N9020A	2025-12-29	2026-12-28
3	MXG RF Vector Signal Generator	Agilent	N5182A	2025-12-29	2026-12-28
Note: The above test equipment is calibrated by Guangzhou LiSai Metrology & Test Co.,Ltd. Calibration method reference Article 24-2, Paragraph 4 of the Radio Act. (method c)					
4	Constant Temperature Humidity Chamber	ZHONGJIAN	ZJ-HWHS80B	2025-08-29	2026-08-28
Note: The test equipment is calibrated by GUANGZHOU NEM METROLOGY&TEST TECHNOLOGY CO.,LTD Calibration method reference Article 24-2, Paragraph 4 of the Radio Act. (method c)					
5	DC Power Supply	IVYTECH	IV3605	2025-09-05	2026-09-04
Note: The test equipment is calibrated by Centre Testing International Group Co., Ltd. (CTI) Calibration method reference Article 24-2, Paragraph 4 of the Radio Act. (method c)					
6	Oscilloscope	Tektronix	MDO3012	2025-09-30	2026-09-29
Note: The test equipment is calibrated by Ti Testing & Certification Group Co., Ltd. Shenzhen Branch Calibration method reference Article 24-2, Paragraph 4 of the Radio Act. (method c)					
Remark: (a) Callbration conducted by the National institute of infommation and Communications Technology (NiCT)in Japan (hereinafter referred to as "NICT") or a designated calbration agency under Article 102-18paragraph (1) in JRL. (b) Correction conducted pursuant to the provisions of Article 135 or Article 144 of the Measurement Act(Act No. 51 of 1992). (c) Calilbration conducted in countries except Japan, which shall be equivalent to the calibration conductedby the NiCT or a designated calibration agency under Article 102-18 paragraph (1). (d) Calibration, etc, conducted by using measuring instruments and other equipment listed in the rightcolumn of appended table No. 3, which shall have been given any type of calbration, etc. listed abovefrom (a)1o (c) From JRL Article 24 .2, paragraph 4, Item 2					

1.8. Description of Test Facility

The test facility is recognized, certified, or accredited by the following organizations:

FCC-Registration No.: 279531

Shenzhen Anbotek Compliance Laboratory Limited, EMC Laboratory has been registered and fully described in a report filed with the (FCC) Federal Communications Commission. The acceptance letter from the FCC is maintained in our files. Registration No. 279531.

Test Location

Shenzhen Anbotek Compliance Laboratory Limited.
Sogood Industrial Zone Laboratory & 1/F. of Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Subdistrict, Bao'an District, Shenzhen, Guangdong, China.

1.9. Disclaimer

1. The test report is invalid if not marked with the signatures of the persons responsible for preparing and approving the test report.
2. The test report is invalid if there is any evidence and/or falsification.
3. The results documented in this report apply only to the tested sample, under the conditions and modes of operation as described herein.
4. This document may not be altered or revised in any way unless done so by Anbotek and all revisions are duly noted in the revisions section.
5. Content of the test report, in part or in full, cannot be used for publicity and/or promotional purposes without prior written approval from the laboratory.
6. The authenticity of the information provided by the customer is the responsibility of the customer and the laboratory is not responsible for its authenticity.
7. The data in this report will be synchronized with the corresponding national market supervision and management departments and cross-border e-commerce platforms as required by regulatory agencies.

The laboratory is only responsible for the data released by the laboratory, except for the part provided by the applicant.

1.10. Measurement Uncertainty

Parameter	Uncertainty
Occupied Bandwidth	552Hz
Conducted Output Power	0.84dB
Conducted Spurious Emission	1.24dB
Frequency tolerance	58Hz
The measurement uncertainty and decision risk evaluated according to AB/WI-RF-F-032. This uncertainty represents an expanded uncertainty expressed at approximately the 95% confidence level using a coverage factor of k=2.	

2. Summary of Test Results

Test Standard	Description of Test	Result
MIC Notice No.88 Appendix No.43 Article 2 Paragraph 1 Item 19	Frequency Tolerance	Complies
	Antenna power	Complies
	EIRP	Complies*
	Antenna Power Tolerance	Complies
	Occupied Bandwidth	Complies
	Spread Bandwidth	N/A
	Spurious Emissions	Complies
	Carrier sensing function 1	N/A**
	Carrier sensing function 2	N/A***
	Interference prevention function	Complies
	Secondary Radiated Emissions	Complies
	Dwell Time	N/A
	Transmission Radiated Angle Width (3dB Beam Bandwidth)	N/A****
	Antenna Absolute Gain	Complies

Note:

(1) N/A is an abbreviation for Not Applicable.

(2) This device have more than 1 subcarrier in 1MHz, compliance with the requirement.

**: Application to Antenna Gain more than 2.14dBi.*

***: Application to transmitting devices which EIRP is less than (2.14dBi + antenna power limit) and the shortage of EIRP is compensated by the antenna power. Not applicable to this product.*

****: Application to transmitting devices with OFDM modulation and the occupied bandwidth greater than 26MHz.*

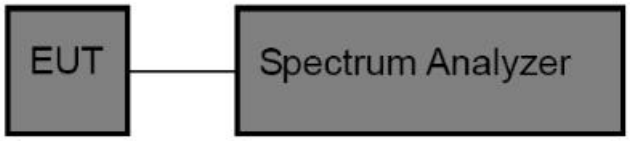
*****: Application to EIRP more than 12.14dBm.*

3. Frequency Tolerance Test

3.1. Test Limit

Test Limit	±50 ppm

3.2. Test Setup



3.3. Test Procedure

Test Frequency= test channel
RBW=VBW=10kHz
Span=500kHz
Sweep time=Auto
Detector mode=Positive peak
Indication mode=Max hold

3.4. Test Data

PASS

Please refer to Appendix A of the Appendix Test Data.

4. Antenna Power Test

4.1. Test Limit

No.	Modulation Method	Frequency Range	Antenna Power	E.I.R.P
1.	FHSS(Compound method with DSSS or OFDM) (OBW within 83.5MHz)	2427-2470.75 MHz	3mW/MHz or less	6.91-16.91dBm/MHz
		2400-2483.5 MHz (except 2427-2470.75MHz)	10mW/MHz or less	12.14-22.14dBm/MHz
2.	DSSS (OBW within 26MHz)	2400 - 2483.5 MHz	10mW/MHz or less	12.14-22.14dBm/MHz
3.	OFDM (OBW within 26MHz)		10mW/MHz or less	12.14- 22.14dBm/MHz
4.	OFDM (OBW 26-40MHz)		5mW/MHz or less	9.13-19.13dBm/MHz
5.	Other Digital methods (OBW within 26MHz)		10mW or less	12.14-22.14dBm
6.	Tolerance	+20%		

4.2. Test Setup

4.3. Test Configuration

1. Search Frequency of Peak Power
   Test Frequency: test channel,
   RBW=VBW≥99% Occupy Bandwidth, Span=4MHz (5MHz for 2M PHY), Sweep time=Auto, Detector mode =Positive peak
2. Antenna power= Peak power

4.4. Test Data

Pass

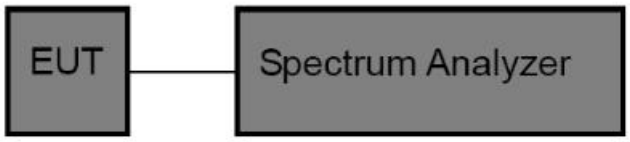
Please refer to Appendix B of the Appendix Test Data.

5. Occupied Bandwidth (99%) Test

5.1. Test Limit

Modulation type	Limit
FH:	83.5MHz or less
FH + DS:	83.5MHz or less
FH + OFDM:	83.5MHz or less
OFDM:	With 20M Bandwidth: 26MHz or less With 40M Bandwidth: 26-40MHz
Others:	26MHz or less

5.2. Test Setup



5.3. Test Procedure

Test Frequency= test channel
RBW=VBW=300kHz
Span=4MHz
Sweep time=Auto
Detector mode=Positive peak
Indication mode=Max hold

5.4. Test Data

PASS

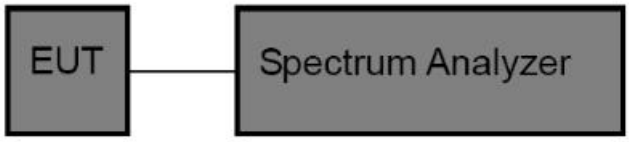
Please refer to Appendix C of the Appendix Test Data.

6. Spurious Emissions Intensity Test

6.1. Test Limit

Frequency Range	Test Limit
≤2387MHz	≤2.5μW/MHz (-26dBm/MHz)
2387MHz to 2400MHz	≤25μW/MHz (-16dBm/MHz)
2483.5MHz to 2496.5MHz	≤25μW/MHz (-16dBm/MHz)
≥2496.5MHz	≤2.5μW/MHz (-26dBm/MHz)

6.2. Test Setup



6.3. Test Procedure

Step 1:
Test Frequency: test channel,
RBW=VBW=1MHz, Sweep time=Auto, Detector mode=Positive peak
Step 2:
Test Frequency: spurious frequency
RBW=VBW=1MHz, Sweep time=Auto, Detector mode=Sample, Span=10MHz

6.4. Test Data

Pass

Please refer to Appendix D of the Appendix Test Data.

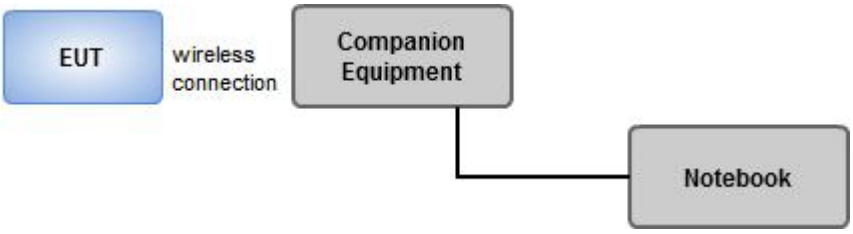
Note: SA set to from 2.4965GHz to 13GHz, plot shows from 2.497GHz to 13GHz as of SA's default format.

7. Interference prevention function

7.1. Test Limit

Test Limit	The identification code shall be 48 bits long

7.2. Test Setup



7.3. Test Configuration

1. Set EUT under operating mode and link up with companion equipment
2. Check communication status between EUT and companion equipment is normal
3. Record the max. reading.
4. Confirm the MAC address of EUT

7.4. Test Data

Test Mode	ID Code	Test Results
BLE	DE:BE:D1:7F:90:6E	Complies

8. Secondary Radiated Emissions Test

8.1. Test Limit

Frequency Range	Test Limit
30~ 1000MHz	≤4.0nW (-54dBm)
1000~ 12500MHz	≤20nW (-47dBm)

8.2. Test Setup

8.3. Test Configuration

Test Frequency: test channel,
Below 1GHz, RBW=VBW=100kHz;
Above 1GHz, RBW=VBW=1MHz,
Sweep time=Auto, Detector mode=Positive peak

Adjust the spectrum analyzer configuration during final testing:Set the spectrum analyzer at the secondary launch measurement as follows.Center frequency secondary firing frequency Sweep frequency width span = 0Hz. If the resolution bandwidth is less than 1 GHz, it is 100 kHz and 1 MHz for 1 GHz or more Same as video bandwidth resolution bandwidth Minimum time guaranteed sweep time measurement accuracy Sweep mode single sweep Detection mode samples or RMS
Any emissions identified during the sweeps exceeds 1/10 of applicable limit, shall be individually measured using RMS detector and compared to the limits

8.4. Test Data

Pass

Please refer to Appendix E of the Appendix Test Data.

APPENDIX I -- TEST SETUP PHOTOGRAPH

Please refer to separated files Appendix I -- Test Setup Photograph_RF

APPENDIX II -- EXTERNAL PHOTOGRAPH

Please refer to separated files Appendix II -- External Photograph

APPENDIX III -- INTERNAL PHOTOGRAPH

Please refer to separated files Appendix III -- Internal Photograph

---------- End of Report ----------